

T495B226K016ATA1K8

T495 Auto, Tantalum, MnO2 Tantalum, Commercial Grade, 22 uF, 10%, 16 VDC, SMD, MnO2, Molded, Low ESR, Auto, AEC-Q200, 1.8 Ohms, 3528, 2.1 mm, 0.8 mm



| General Information | |
|--------------------------|---|
| Series | T495 Auto |
| Dielectric | MnO2 Tantalum |
| Style | SMD Chip |
| Description | SMD, MnO2, Molded, Low ESR, Auto, AEC-Q200 |
| Features | Low ESR, Automotive |
| RoHS | Yes |
| Termination | Tin |
| Qualifications | AEC-Q200 |
| AEC-Q200 | Yes |
| Typical Component Weight | 107.45 mg |
| | |

| Dimensions | |
|------------|--------------------|
| L | 3.5mm +/-0.2mm |
| W | 2.8mm +/-0.2mm |
| Н | 1.9mm +/-0.2mm |
| T | 0.13mm REF |
| S | 0.8mm +0.1/-0.3mm |
| F | 2.2mm +/-0.1mm |
| Α | 1.9mm MIN |
| В | 0.4mm +/-0.15mm |
| E | 2.2mm REF |
| G | 1.8mm REF |
| P | 0.5mm REF |
| R | 1mm REF |
| X | 0.1mm +/-0.1mm REF |

| Specifications | |
|--------------------|--|
| Capacitance | 22 uF |
| Tolerance | 10% |
| Voltage DC | 16 VDC (85C), 10.72 VDC (125C) |
| Temperature Range | -55/+125°C |
| Rated Temperature | 85°C |
| Dissipation Factor | 6% 120Hz 25C |
| Failure Rate | N/A |
| ESR | 1800 mOhms (100kHz 25C) |
| Ripple Current | 217 mA (rms, 100kHz 25C), 195.3 mA (rms, 85C), 86.8 mA (rms, 125C) |
| Leakage Current | 3.5 uA (5min 25°C) |

| Packaging Specifications | |
|--------------------------|------------|
| Packaging | T&R, 178mm |
| Packaging Quantity | 2000 |

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